

Results for "(((wires <and> terminals <and> connector)<in>metadata)) <and> (pyr >= 1951 <and> pyr <= 1996))"
 Your search matched 8 of 1144303 documents.
 A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

e-mail print

[View Session History](#)

[New Search](#)

» Key

IEEE JNL IEEE Journal or Magazine
 IEE JNL IEE Journal or Magazine
 IEEE CNF IEEE Conference Proceeding
 IEE CNF IEE Conference Proceeding
 IEEE STD IEEE Standard

Modify Search

☐ Check to search only within this results set

Display Format: ☒ Citation ☐ Citation & Abstract

Select Article Information

- ☐ 1. **Is multiplexing the answer?**
 Spiers, J.W.;
 Connectors on Vehicles, IEE Colloquium on
 13 Apr 1989 Page(s):6/1 - 6/6
[AbstractPlus](#) | Full Text: [PDF\(28 KB\)](#) IEE CNF
- ☐ 2. **Reference Connectors for Evaluation of Aluminium Building-Wire Connectability**
 Bond, N.;
 Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [see also IEEE Trans. on Component and Manufacturing Technology, Part A, B, C]
 Volume 4, Issue 1, Mar 1981 Page(s):41 - 44
[AbstractPlus](#) | Full Text: [PDF\(536 KB\)](#) IEEE JNL
- ☐ 3. **Evaluation of receptacle connections and contacts**
 Aronstein, J.;
 Electrical Contacts, 1993., Proceedings of the Thirty-Ninth IEEE Holm Conference on
 27-29 Sept. 1993 Page(s):253 - 260
[AbstractPlus](#) | Full Text: [PDF\(2140 KB\)](#) IEEE CNF
- ☐ 4. **IEE Colloquium on 'New Techniques In Providing Customer Services with Copper' (Digest No.149)**
 New Techniques in Providing Customer Services with Copper, IEE Colloquium on
 7 Dec 1989
[AbstractPlus](#) | Full Text: [PDF\(24 KB\)](#) IEE CNF
- ☐ 5. **Dynamic finite element analysis simulation of the terminal crimping process**
 Villeneuve, G.; Kulkarni, D.; Bastnagel, P.; Berry, D.;
 Electrical Contacts, 1996., Proceedings of the Forty-Second IEEE Holm Conference on ? Joint with the 18th Interna
 Conference on Electrical Contacts
 16-20 Sept. 1996 Page(s):156 - 172
[AbstractPlus](#) | Full Text: [PDF\(1136 KB\)](#) IEEE CNF
- ☐ 6. **Aspects of Accelerated Aging Tests Used on Connectors and Terminals for the U.K. External Telephone Ne**
 Wiltshire, B.;
 Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [see also IEEE Trans. on Component and Manufacturing Technology, Part A, B, C]
 Volume 6, Issue 1, Mar 1983 Page(s):21 - 27
[AbstractPlus](#) | Full Text: [PDF\(1216 KB\)](#) IEEE JNL
- ☐ 7. **A Broad-Band Microwave Coaxial Connector with Capacitive RF Coupling and Isolated DC Returns (Corresp**
 Lin, C.M.; Grow, R.W.;
 Microwave Theory and Techniques, IEEE Transactions on
 Volume 6, Issue 4, Oct 1958 Page(s):454 - 454
[AbstractPlus](#) | Full Text: [PDF\(152 KB\)](#) IEEE JNL



8. Solderless high-density Interconnects for burn-In applications

Guarin, F.J.; Katsetos, A.A.;

Electronic Components and Technology Conference, 1992. Proceedings., 42nd

18-20 May 1992 Page(s):263 - 267

[AbstractPlus](#) | Full Text: [PDF\(568 KB\)](#) IEEE CNF



[Help](#) [Contact Us](#) [Privacy & Se](#)

© Copyright 2005 IEEE – A

Indexed by
 Inspec